


<b>Search Notes</b>  	<b>Application/Control No.</b>  10516971	<b>Applicant(s)/Patent Under Reexamination</b>  YOSHIKAWA ET AL.
	<b>Examiner</b>  CECILIA M JAISLE	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
544	262	7/1/2008	C. Jaisle
514	248	7/1/2008	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STIC searched Inventor Names & STN	7/1/2008	C. Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
544	262	7/1/2008	C. Jaisle
514	248	7/1/2008	C. Jaisle